



EIA STANDARD

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Lightning Strike Test Procedure for Electrical Connectors

EIA-364-75A

(Revision of EIA-364-75)

January 2009



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(From Standards Proposal No. 5175, formulated under the cognizance of the CE-2.0 Committee on EIA National Connector and Socket Standards, and reaffirmed per Standards Proposal No. 5346.06).

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TEST PROCEDURE No. 75A
LIGHTNING STRIKE TEST PROCEDURE
FOR
ELECTRICAL CONNECTORS

(From EIA Standards Proposal No. 5175, formulated under the cognizance EIA CE-2.0 Committee on National Connector Standards, and previously published as EIA-364-75.)

1 Introduction

1.1 Content

This standard establishes a test method to determine the capability of a connector pair to conduct the electrical current induced by a lightning strike. The results derived may be used to determine whether the contacts within the inserts will be adequately protected from flashover and whether the connector shells will adequately conduct lightning currents.

NOTE — Coupling torque, shell-to-shell conductance, and dielectric withstanding voltage are integral measurements to be performed as part of this test procedure, so they are included in the document, (creating a test sequence).

1.2 Definitions

1.2.1 Test article

A general term used to refer to a mated connector pair.

1.3 Abbreviations and symbols

A	amperes
CUT	connector under test
I _{pk}	peak current
kA	kiloamperes
mV	millivolts
μs	microseconds
t	time
UUT	unit under test

